

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10769786	CHOI ET AL.
	Examiner Nguyen, Jennifer T	Art Unit 2629

SEARCHED

Class	Subclass	Date	Examiner
345	60-72,88-104,33,41,42	1/19/08	JN

SEARCH NOTES

Search Notes	Date	Examiner
east, iEEE, JPO,EPO, USPAT, US-PGPUB, DERWENT,Inventor, Claim interference	1/19/08	JN

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
315	169.1,169.4	1/19/08	JN
313	582-586	1/19/08	jn